

**Search Notes**

Application/Control No.

10/777,102

Examiner

José R. Díaz

Applicant(s)/Patent under  
Reexamination

YUN ET AL.

Art Unit

2815

**SEARCHED**

Class	Subclass	Date	Examiner
438	411,455,4 56	7/17/2006	JRD
257	e23.013	7/17/2006	JRD

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Text Search East See search history printout	7/17/2006	JRD